



SEMI® International Standards Program

Compound Semiconductor Technical Committee Meeting

Virtual Meeting (Videoconference)

**Tuesday 09th April 2024,
16:30 CEST / 7:30 am PDT / 23:30 J**

V1 21.02.2024

Co-chairs:

- [Dr. Arnd-Dietrich Weber, SiCrystal](#)
- [N.N.](#)

European Compound Semiconductor Committee Meeting (Virtual Meeting)

16:30	Welcome and Self-Introductions	all
16:40	SEMI Standards Overview and Legal Reminders	SEMI Staff
16:45	Review of the minutes and action items from the previous meeting	SEMI Staff
16:55	Task Force Reports (~5 minutes each) • SiC-Task Force • 5-year Review (M46, M63, M75) Task Force • Test Method for SiC -Task Force • SiC Epi Defects Task Force • Silicon Carbide Engineered Substrate Task Force	A. Weber H.C. Alt C. Kranert C. Kranert C. Cela
17:20	SNARF approval: New Standard: Specification for Silicon Carbide Engineered Substrate	C. Cela
17:25	Ballot Review: Doc. 7161, Line-Item Revision of SEMI M93-0923 Test Method For Quantifying Basal Plane Dislocation Density In 4H-SiC By X-Ray Diffraction Topography/Imaging	C. Kranert
18:00	Compound Materials Liaison Reports • North America • Japan • China	SEMI Staff
18:10	New Business: • Review of document-status and upcoming-reviews • Open discussion	A. Weber N.N.
18:20	Any Other Business / Questions	A. Weber
18:25	Next Meetings	
18:30	End	